

As might be expected, the temperature dependence of the mobility of the carriers in the grain-boundary space-charge sheath is such as to indicate that the principle scattering mechanism is impurity or defect scattering. However, the marked difference between the mobilities (Fig. 9) of samples with different orientation of the grain boundary is not understood.

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Hot Electron Problem in Semiconductors with Spheroidal Energy Surfaces

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Shockley has derived the expression $E_c = (1.51)C_l/\mu$ for the critical electric field strength E_c at which the current-voltage relation in a semiconductor departs from Ohm's law. Here C_l is the velocity of longitudinal phonons and μ the conductivity mobility of the carrier. Experimental values of E_c for Ge and Si are from two to four times larger than those predicted by this formula. We therefore have extended the theory to take account ellipsoidal energy surfaces in the Brillouin Zone and scattering by shear modes of vibration. The effect of the more general effective mass tensor is to raise the theoretical value of E_c by a factor of about 2 for n -type Ge and 1.3 for n -type Si, whereas shear mode scattering lowers E_c by a factor that is between 1 and the value of the ratio of the velocity of transverse modes to that of longitudinal modes. Moreover, E_c should vary with the direction of the current. The present study still fails to close the gap between theory and experiment: the remaining discrepancy is possibly the result of neglecting intervalley scattering.

INTRODUCTION AND SUMMARY

THE deviation from Ohm's law in semiconductors such as Ge and Si in strong electric fields has been studied both theoretically¹⁻⁷ and experimentally^{8,9} by many investigators. This problem has been called the "hot-electron" problem by Shockley because the average kinetic energy of the electrons in strong fields becomes larger than the usual thermal energy, so that the "electron temperature" becomes larger than the lattice temperature. There are, however, quantitative discrepancies between theory and experiment in some respects, such as in the value of the critical field E_c where the deviation from Ohm's law occurs. The experimental values in Ge and Si are about twice to four times larger than those obtained from the formula

$$E_c^s = 1.51C_l/\mu. \quad (1)$$

The superscript s on E_c indicates that this value is obtained from the scalar effective mass theories, C_l is the longitudinal velocity of the phonons, and μ is the weak-field conductivity mobility of electrons.

Previous calculations have assumed spherical energy

surfaces in the Brillouin zone. It is now believed that for n -type Ge and Si one must use spheroidal surfaces in discussing the electrical properties. Further, as has been pointed out by Adams¹⁰ and by Herring,¹¹ shear waves are as important as pure compressional waves in the lattice scattering of electrons in these crystals. Therefore we have attempted to solve the hot-electron problem with the spheroidal model, including the effect of shear waves. A number of drastic approximations are made in solving the Bloch equation, and we finally get the expression for the critical field in the following form:

$$E_c = ASE_c^s, \quad (2)$$

where the factor A is an anisotropy factor and the other factor S results from the effect of the shear waves. When we neglect the effect of the latter, S equals 1, and when the mass component ratio $r = m_2/m_1$ is equal to 1, A becomes independent of the direction of the current vector and is also 1. The larger the departure of r from 1, the larger is the value of A . The factor S is a complicated function of the mass ratio r , the ratios of the characteristic coefficients of the deformation potentials of shear waves and of pure compressional waves, and the ratio $C = C_t/C_l$ of the transverse and longitudinal velocities of the acoustical modes of lattice vibration. However, the value of S is almost always between C and 1. This fact may be qualitatively understood, because both

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⁹ E. J. Ryder, Phys. Rev. **90**, 766 (1953).

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¹¹ C. Herring, "Transport properties of a many-valley semiconductor" September, 1954 (unpublished).

Here μ is the weak field conductivity mobility defined by

$$\mu = \frac{2(2\pi)^{3/2} e \hbar^4 M C_i^2}{3 E_d^2 (kT)^{3/2} \sqrt{\Delta}} \left(\frac{\text{Trace} \mathfrak{M}^{-1}}{3} \right) \frac{1}{(1+2b\delta+c\delta^2)}, \quad (11)$$

and p is defined by

$$p = \frac{3\pi}{16} \left(\frac{\mu}{C_i} \right)^2 \left(\frac{1+2b\delta+c\delta^2}{1+2a\delta+a\delta^2} \right) \left(\frac{3}{\text{Trace} \mathfrak{M}^{-1}} \right)^2 \times \left(\frac{3}{\text{Trace} \mathfrak{M}} \right) F \cdot \mathfrak{M}^{-1} \cdot F. \quad (12)$$

Here Δ is the determinant of the mass tensor and the three constants a , b , and c are functions of r and C given by

$$a = 1/(2r+1), \quad (13)$$

$$b = \left[\frac{2(\sqrt{r+3})}{3(\sqrt{r+1})^3} + \frac{2r^2 \ln r}{(r-1)^3} - \frac{(3r-1)}{(r-1)^2} \right], \quad (14)$$

$$c = Cb + \frac{(1-C)}{3} \left[\frac{2}{(\sqrt{r+1})^4} + \frac{(2r^2+5r-1)}{(r-1)^3} - \frac{6r^2 \ln r}{(r-1)^4} \right]. \quad (15)$$

In order to discuss the hot-electron problem in actual crystals such as Ge and Si, we must consider the several spheroids in the Brillouin zone and sum up each current density (10) of these spheroids. Three special cases are considered: Case (A): 6 (or 3) spheroids along the cubic axes, Case (B): 12 spheroids along the face-diagonal axes, Case (C): 8 (or 4) spheroids along the body-diagonal axes.

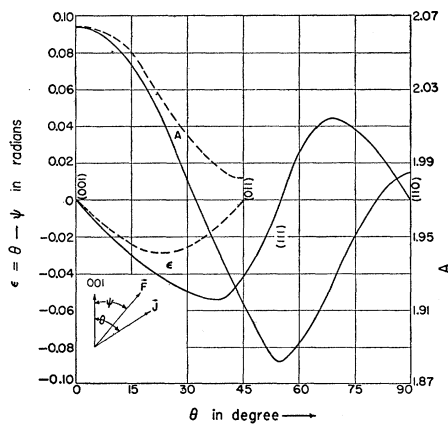


FIG. 2. A and ϵ versus θ in Case (C) with $r=0.06$. Here $\epsilon = \theta - \psi$; θ and ψ are the polar angles with respect to the Z -axis of current and field vectors respectively. For full curves these vectors are lying in the $X=Y$ plane and for broken curves they are lying in the $X=0$ plane.

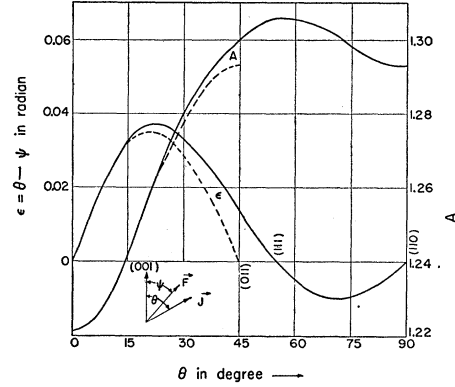


FIG. 3. A and ϵ versus θ in Case (A) with $r=0.2$.

The total current density J_T is given in each case by

$$J_T = \frac{N e \mu \pi}{2^{5/4} \Gamma(3/4)} \left(\frac{3}{\text{Trace} \mathfrak{M}^{-1}} \right) \frac{1}{n} \sum_{i=1}^n p_i^{-1} \mathfrak{M}_i^{-1} \cdot \mathbf{F}, \quad (16)$$

where N is the total carrier density and n is the number of spheroids. Here p_i is a function of the electric field vector and of the direction of the rotational axis of the i th spheroid. Two factors A and S already introduced in Eq. (2) are derived from Eq. (16):

$$S = \left\{ \frac{1+2a\delta+a\delta^2}{1+2b\delta+c\delta^2} \right\}^{1/2}, \quad (17)$$

$$A = A_1 \frac{3}{(r+2)} \left(\frac{2r+1}{3r} \right)^{3/2}. \quad (18)$$

Here A_1 is dependent not only upon r but also upon both the spheroid arrangement and the direction of the current vector. In Table I, expressions for $\sqrt{A_1}$ are listed for the cases in which the current vector is directed along three symmetry axes of the cubic crystal. In Fig. 1, three S curves are plotted as a function of δ for $r=0.04$, 1 and 9, where we use 0.431 as the value of C . The anisotropy factor A and the deviation angle ϵ between the current and field vectors are the measures of the anisotropy in the hot-electron problem. They are plotted as functions of the direction of the current vector in Figs. 2 and 3, for n -type Ge and Si, respectively. In Fig. 2 we use the arrangement (C) with $r=0.2$. Two special cases are considered in these figures: For broken curves we let the current vector lie in the $X=0$ plane; the field vector then makes an angle ϵ with the current vector and lies in the same plane. For full curves both current and field vectors lie in the $X=Y$ plane.

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